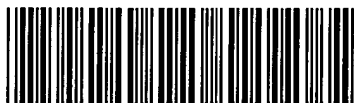


**Search Notes**

Application/Control No.

10/603,493

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

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Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	11	6/11/2005	PK
709	202,203	6/11/2005	PK
340	7.29	6/11/2005	PK
370	395.52	6/11/2005	PK
379	88.17	6/11/2005	PK
Above	updated	11/26/2005	PK
Above	new	11/26/2005	PK
Above	new	12/7/2005	PK
Above	updated	1/7/2006	PK
Above	updated	2/4/2006	PK
Above	updated	8/17/2006	PK
Above	new	8/17/2006	PK
Above	updated	3/1/2007	PK
Above	new	3/1/2007	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Classes/Sub searched: 716/1-18; 709/all; 340/all; 370/all (see attached)	6/11/2005	PK
Above upaded and new search (see attached)	11/26/2005	PK
Above new search (see attached)	12/7/2005	PK
Above updated search (see attached)	1/7/2006	PK
Above updated search (see attached)	2/4/2006	PK
Above updated and new search (see attached)	8/17/2006	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	6/11/2005	PK
IEE/IEEE Xplore (see attached)	12/7/2005	PK

**Search Notes (continued)**

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	DATE	EXMR
IEE/IEEE Xplore (see attached)	12/7/2005	PK
BRS (EAST) (updated and new search): --USPAT, USPGPUBClasses/Sub searched: 716/1-18; 709/all; 340/all; 370/all (see attached)	3/1/2007	PK
IEE/IEEE Xplore (see attached) --New search	3/1/2007	PK